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|-----------------------------------|---------------------------------------|---|-------------|
| <b>Notice of References Cited</b> | Application/Control No.<br>09/009,837 | Applicant(s)/Patent Under<br>Reexamination<br>MILLS, RANDELL L. |             |
|                                   | Examiner<br>Susy N Tsang-Foster       | Art Unit<br>1745  | Page 1 of 1 |

**U.S. PATENT DOCUMENTS**

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